


<b>Search Notes</b>  	<b>Application/Control No.</b>  10565833	<b>Applicant(s)/Patent Under Reexamination</b>  YAMANAKA ET AL.
	<b>Examiner</b>  HIEN NGUYEN	<b>Art Unit</b>  3768

SEARCHED			
Class	Subclass	Date	Examiner
600	476	11/18/2008	HN

SEARCH NOTES		
Search Notes	Date	Examiner
East Search (inventor search, multichannel photometric instrument, light, measuring, medium, scattering, body, light measuring device or instrument or apparatus)	11/18/2008	HN
East Search (search ep 1245192 for us equivalent us patent and pgpub).	8/6/2009	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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